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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

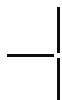
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	249
Number of Gates	48000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	329-BBGA
Supplier Device Package	329-PBGA (31x31)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/a54sx32-bg329">https://www.e-xfl.com/product-detail/microchip-technology/a54sx32-bg329</a>



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# SX Family FPGAs

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## General Description

The Actel SX family of FPGAs features a sea-of-modules architecture that delivers device performance and integration levels not currently achieved by any other FPGA architecture. SX devices greatly simplify design time, enable dramatic reductions in design costs and power consumption, and further decrease time to market for performance-intensive applications.

The Actel SX architecture features two types of logic modules, the combinatorial cell (C-cell) and the register cell (R-cell), each optimized for fast and efficient mapping of synthesized logic functions. The routing and interconnect resources are in the metal layers above the logic modules, providing optimal use of silicon. This enables the entire floor of the device to be spanned with an uninterrupted grid of fine-grained, synthesis-friendly logic modules (or “sea-of-modules”), which reduces the distance signals have to travel between logic modules. To minimize signal propagation delay, SX devices employ both local and general routing resources. The high-speed local routing resources (DirectConnect and FastConnect) enable very fast local signal propagation that is optimal for fast counters, state machines, and datapath logic. The general system of segmented routing tracks allows any logic module in the array to be connected to any other logic or I/O module. Within this system, propagation delay is minimized by limiting the number of antifuse interconnect elements to five (90 percent of connections typically use only three antifuses). The unique local and general routing structure featured in SX devices gives fast and predictable performance, allows 100 percent pin-locking with full logic utilization, enables concurrent PCB development, reduces design time, and allows designers to achieve performance goals with minimum effort.

Further complementing SX’s flexible routing structure is a hardwired, constantly loaded clock network that has been tuned to provide fast clock propagation with minimal clock skew. Additionally, the high performance of the internal logic has eliminated the need to embed latches or flip-flops in the I/O cells to achieve fast clock-to-out or fast input setup times. SX devices have easy to use I/O cells that do not require HDL instantiation, facilitating design reuse and reducing design and verification time.

## SX Family Architecture

The SX family architecture was designed to satisfy next-generation performance and integration requirements for production-volume designs in a broad range of applications.

### Programmable Interconnect Element

The SX family provides efficient use of silicon by locating the routing interconnect resources between the Metal 2 (M2) and Metal 3 (M3) layers (Figure 1-1 on page 1-2). This completely eliminates the channels of routing and interconnect resources between logic modules (as implemented on SRAM FPGAs and previous generations of antifuse FPGAs), and enables the entire floor of the device to be spanned with an uninterrupted grid of logic modules.

Interconnection between these logic modules is achieved using The Actel patented metal-to-metal programmable antifuse interconnect elements, which are embedded between the M2 and M3 layers. The antifuses are normally open circuit and, when programmed, form a permanent low-impedance connection.

The extremely small size of these interconnect elements gives the SX family abundant routing resources and provides excellent protection against design pirating. Reverse engineering is virtually impossible because it is extremely difficult to distinguish between programmed and unprogrammed antifuses, and there is no configuration bitstream to intercept.

Additionally, the interconnect elements (i.e., the antifuses and metal tracks) have lower capacitance and lower resistance than any other device of similar capacity, leading to the fastest signal propagation in the industry.

### Logic Module Design

The SX family architecture is described as a “sea-of-modules” architecture because the entire floor of the device is covered with a grid of logic modules with virtually no chip area lost to interconnect elements or routing. The Actel SX family provides two types of logic modules, the register cell (R-cell) and the combinatorial cell (C-cell).

## Routing Resources

Clusters and SuperClusters can be connected through the use of two innovative local routing resources called *FastConnect* and *DirectConnect*, which enable extremely fast and predictable interconnection of modules within clusters and SuperClusters (Figure 1-5 and Figure 1-6). This routing architecture also dramatically reduces the number of antifuses required to complete a circuit, ensuring the highest possible performance.

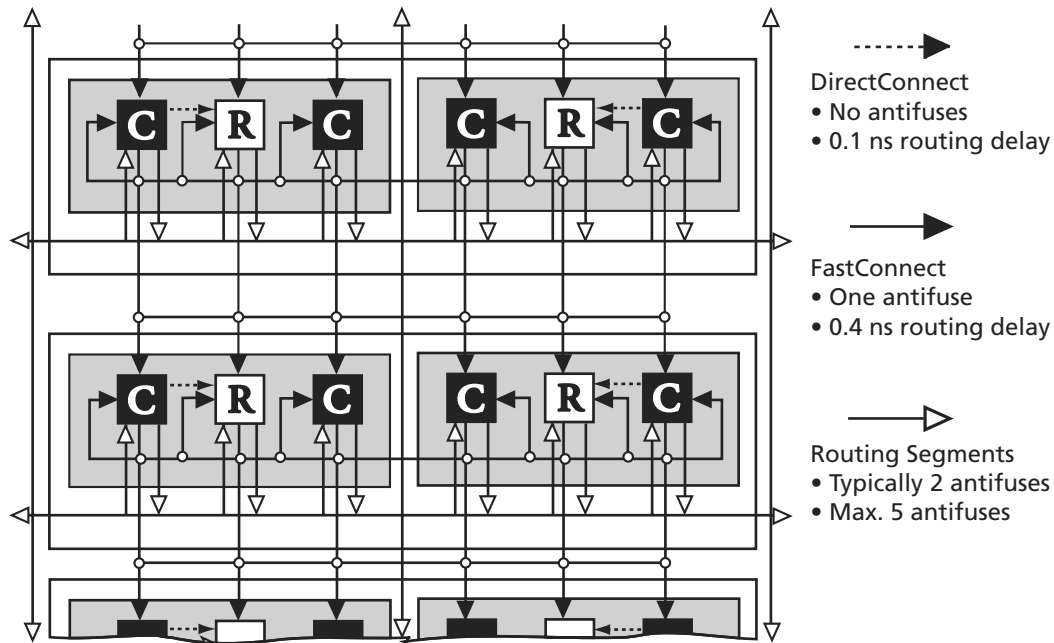


Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters

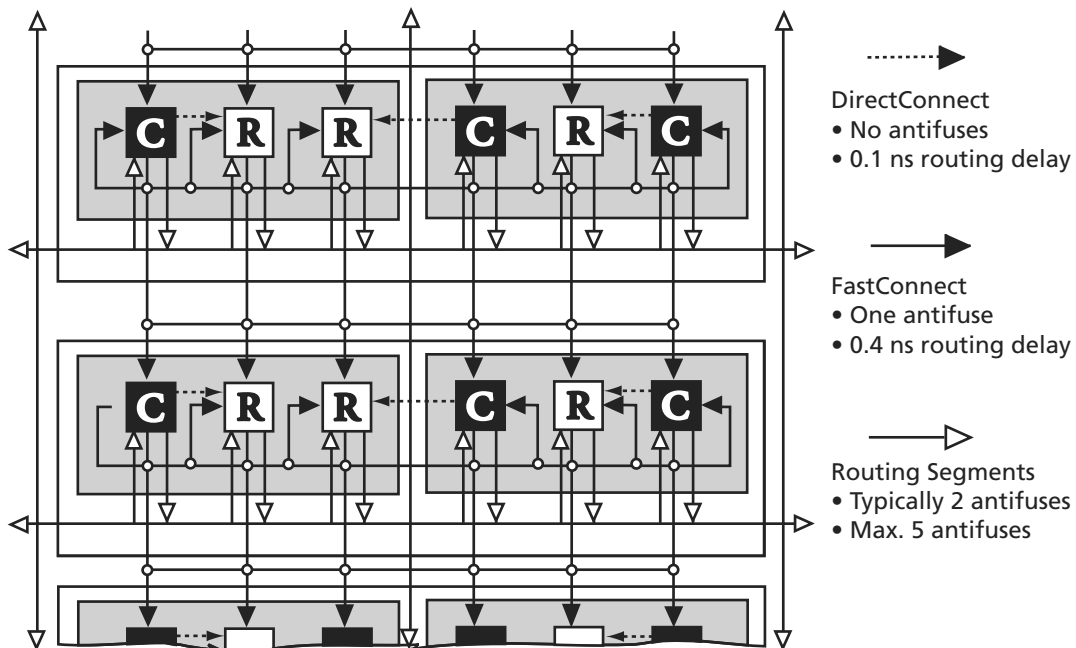


Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

DirectConnect is a horizontal routing resource that provides connections from a C-cell to its neighboring R-cell in a given SuperCluster. DirectConnect uses a hardwired signal path requiring no programmable interconnection to achieve its fast signal propagation time of less than 0.1 ns.

FastConnect enables horizontal routing between any two logic modules within a given SuperCluster and vertical routing with the SuperCluster immediately below it. Only one programmable connection is used in a FastConnect path, delivering maximum pin-to-pin propagation of 0.4 ns.

In addition to DirectConnect and FastConnect, the architecture makes use of two globally oriented routing resources known as segmented routing and high-drive routing. The Actel segmented routing structure provides a variety of track lengths for extremely fast routing between SuperClusters. The exact combination of track lengths and antifuses within each path is chosen by the 100 percent automatic place-and-route software to minimize signal propagation delays.

The Actel high-drive routing structure provides three clock networks. The first clock, called HCLK, is hardwired from the HCLK buffer to the clock select multiplexer (MUX) in each R-cell. This provides a fast propagation path for the clock signal, enabling the 3.7 ns clock-to-out (pin-to-pin) performance of the SX devices. The hardwired clock is tuned to provide clock skew as low as 0.25 ns. The remaining two clocks (CLKA, CLKB) are global clocks that can be sourced from external pins or from internal logic signals within the SX device.

## Other Architectural Features

### Technology

The Actel SX family is implemented on a high-voltage twin-well CMOS process using 0.35  $\mu$  design rules. The metal-to-metal antifuse is made up of a combination of amorphous silicon and dielectric material with barrier metals and has a programmed ("on" state) resistance of 25  $\Omega$  with a capacitance of 1.0 fF for low signal impedance.

## Performance

The combination of architectural features described above enables SX devices to operate with internal clock frequencies exceeding 300 MHz, enabling very fast execution of even complex logic functions. Thus, the SX family is an optimal platform upon which to integrate the functionality previously contained in multiple CPLDs. In addition, designs that previously would have required a gate array to meet performance goals can now be integrated into an SX device with dramatic improvements in cost and time to market. Using timing-driven place-and-route tools, designers can achieve highly deterministic device performance. With SX devices, designers do not need to use complicated performance-enhancing design techniques such as the use of redundant logic to reduce fanout on critical nets or the instantiation of macros in HDL code to achieve high performance.

## I/O Modules

Each I/O on an SX device can be configured as an input, an output, a tristate output, or a bidirectional pin.

Even without the inclusion of dedicated I/O registers, these I/Os, in combination with array registers, can achieve clock-to-out (pad-to-pad) timing as fast as 3.7 ns. I/O cells that have embedded latches and flip-flops require instantiation in HDL code; this is a design complication not encountered in SX FPGAs. Fast pin-to-pin timing ensures that the device will have little trouble interfacing with any other device in the system, which in turn enables parallel design of system components and reduces overall design time.

## Power Requirements

The SX family supports 3.3 V operation and is designed to tolerate 5.0 V inputs. (Table 1-1). Power consumption is extremely low due to the very short distances signals are required to travel to complete a circuit. Power requirements are further reduced because of the small number of low-resistance antifuses in the path. The antifuse architecture does not require active circuitry to hold a charge (as do SRAM or EPROM), making it the lowest power architecture on the market.

Table 1-1 • Supply Voltages

Device	V <sub>CCA</sub>	V <sub>CCI</sub>	V <sub>CCR</sub>	Maximum Input Tolerance	Maximum Output Drive
A54SX08 A54SX16 A54SX32	3.3 V	3.3 V	5.0 V	5.0 V	3.3 V
A54SX16-P*	3.3 V	3.3 V	3.3 V	3.3 V	3.3 V
	3.3 V	3.3 V	5.0 V	5.0 V	3.3 V
	3.3 V	5.0 V	5.0 V	5.0 V	5.0 V

**Note:** \*A54SX16-P has three different entries because it is capable of both a 3.3 V and a 5.0 V drive.

## Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 k $\Omega$ . TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • Boundary Scan Pin Functionality

Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 k $\Omega$ on TMS.

## Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

## Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, ModelSim® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

## Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

## Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

Figure 1-7 • Device Selection Wizard

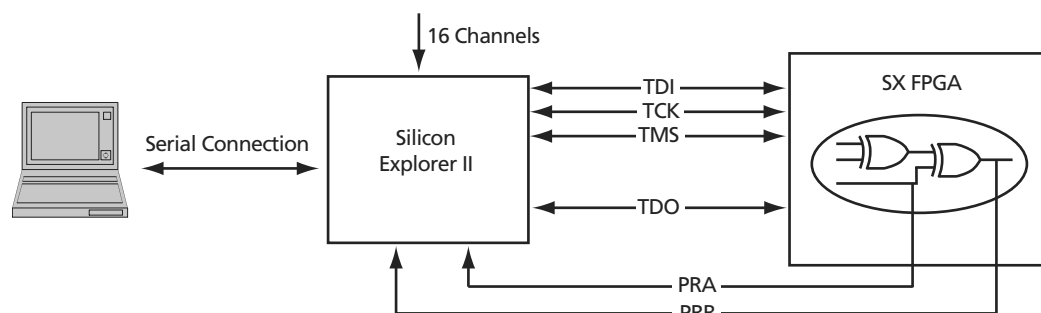


Figure 1-8 • Probe Setup

## Programming

Device programming is supported through Silicon Sculptor series of programmers. In particular, Silicon Sculptor II are compact, robust, single-site and multi-site device programmer for the PC.

With standalone software, Silicon Sculptor II allows concurrent programming of multiple units from the same PC, ensuring the fastest programming times possible. Each fuse is subsequently verified by Silicon Sculptor II to insure correct programming. In addition, integrity tests ensure that no extra fuses are programmed. Silicon Sculptor II also provides extensive hardware self-testing capability.

The procedure for programming an SX device using Silicon Sculptor II are as follows:

1. Load the .AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Actel offers device volume-programming services either through distribution partners or via in-house programming from the factory.

For more details on programming SX devices, refer to the *Programming Antifuse Devices* application note and the *Silicon Sculptor II User's Guide*.

## 3.3 V / 5 V Operating Conditions

Table 1-3 • Absolute Maximum Ratings<sup>1</sup>

Symbol	Parameter	Limits	Units
$V_{CCR}^2$	DC Supply Voltage <sup>3</sup>	-0.3 to + 6.0	V
$V_{CCA}^2$	DC Supply Voltage	-0.3 to + 4.0	V
$V_{CCI}^2$	DC Supply Voltage (A54SX08, A54SX16, A54SX32)	-0.3 to + 4.0	V
$V_{CCI}^2$	DC Supply Voltage (A54SX16P)	-0.3 to + 6.0	V
$V_I$	Input Voltage	-0.5 to + 5.5	V
$V_O$	Output Voltage	-0.5 to + 3.6	V
$I_{IO}$	I/O Source Sink Current <sup>3</sup>	-30 to + 5.0	mA
$T_{STG}$	Storage Temperature	-65 to +150	°C

### Notes:

1. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the Recommended Operating Conditions.
2.  $V_{CCR}$  in the A54SX16P must be greater than or equal to  $V_{CCI}$  during power-up and power-down sequences and during normal operation.
3. Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than  $V_{CC} + 0.5$  V or less than  $GND - 0.5$  V, the internal protection diodes will forward-bias and can draw excessive current.

## A54SX16P AC Specifications for (PCI Operation)

Table 1-7 • A54SX16P AC Specifications for (PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4^1$	-44		mA
		$1.4 \leq V_{OUT} < 2.4^1, ^2$	$-44 + (V_{OUT} - 1.4)/0.024$		mA
		$3.1 < V_{OUT} < V_{CC}^{1, ^3}$		EQ 1-1 on page 1-11	
	(Test Point)	$V_{OUT} = 3.1^3$		-142	mA
$I_{OL(AC)}$	Switching Current High	$V_{OUT} \geq 2.2^1$	95		mA
		$2.2 > V_{OUT} > 0.55^1$	$V_{OUT}/0.023$		
		$0.71 > V_{OUT} > 0^{1, ^3}$		EQ 1-2 on page 1-11	mA
	(Test Point)	$V_{OUT} = 0.71^3$		206	mA
$I_{CL}$	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load <sup>4</sup>	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load <sup>4</sup>	1	5	V/ns

### Notes:

1. Refer to the *V<sub>I</sub>* curves in Figure 1-9 on page 1-11. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half-size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.
3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 1-9 on page 1-11. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur, and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.

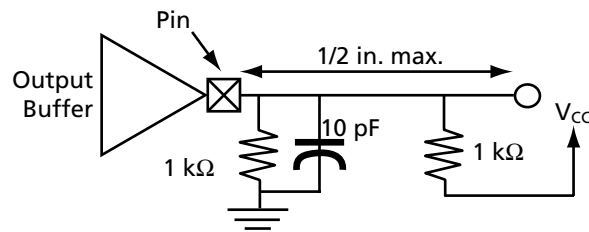




Figure 1-10 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the A54SX16P device.

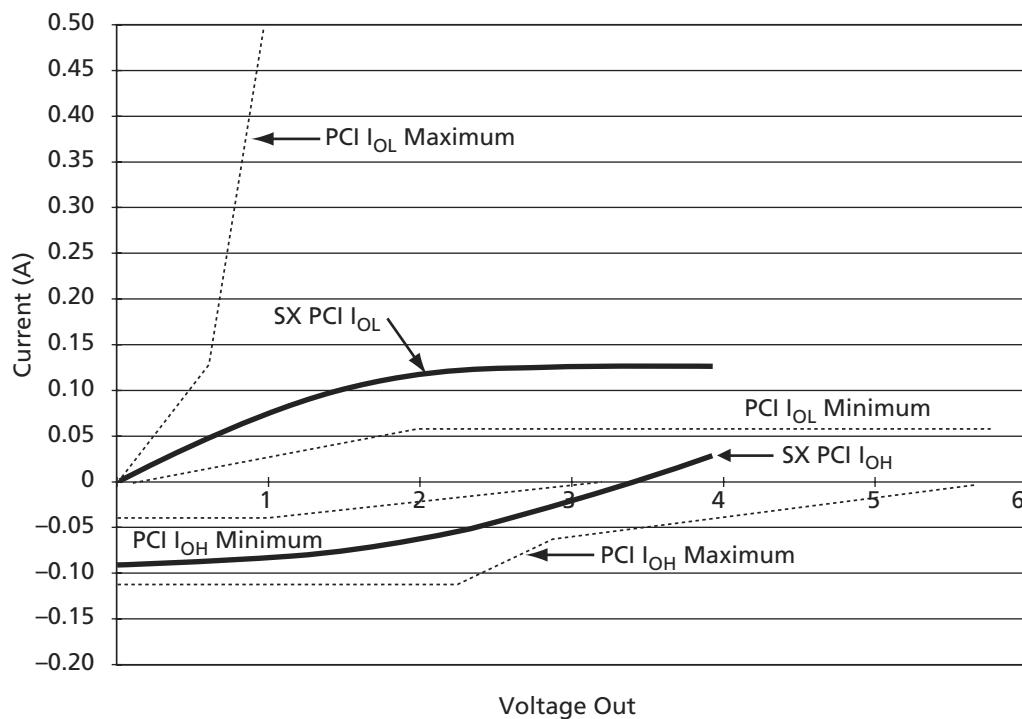


Figure 1-10 • 3.3 V PCI Curve for A54SX16P Device

$$I_{OH} = (98.0/V_{CC}) \times (V_{OUT} - V_{CC}) \times (V_{OUT} + 0.4V_{CC})$$

for  $V_{CC} > V_{OUT} > 0.7 V_{CC}$

EQ 1-3

$$I_{OL} = (256/V_{CC}) \times V_{OUT} \times (V_{CC} - V_{OUT})$$

for  $0 V < V_{OUT} < 0.18 V_{CC}$

EQ 1-4

## A54SX16 Timing Characteristics

Table 1-18 • **A54SX16 Timing Characteristics**  
(Worst-Case Commercial Conditions,  $V_{CCR} = 4.75\text{ V}$ ,  $V_{CCA}, V_{CCI} = 3.0\text{ V}$ ,  $T_J = 70^\circ\text{C}$ )

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays <sup>1</sup>										
t <sub>PD</sub>	Internal Array Module	0.6		0.7		0.8		0.9		ns
Predicted Routing Delays <sup>2</sup>										
t <sub>DC</sub>	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t <sub>FC</sub>	FO = 1 Routing Delay, Fast Connect	0.3		0.4		0.4		0.5		ns
t <sub>RD1</sub>	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t <sub>RD2</sub>	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t <sub>RD3</sub>	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t <sub>RD4</sub>	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t <sub>RD8</sub>	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t <sub>RD12</sub>	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns
R-Cell Timing										
t <sub>RCO</sub>	Sequential Clock-to-Q	0.8		1.1		1.2		1.4		ns
t <sub>CLR</sub>	Asynchronous Clear-to-Q	0.5		0.6		0.7		0.8		ns
t <sub>PRESET</sub>	Asynchronous Preset-to-Q	0.7		0.8		0.9		1.0		ns
t <sub>SUD</sub>	Flip-Flop Data Input Set-Up	0.5		0.5		0.7		0.8		ns
t <sub>HD</sub>	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t <sub>WASYN</sub>	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t <sub>INYH</sub>	Input Data Pad-to-Y HIGH	1.5		1.7		1.9		2.2		ns
t <sub>INYL</sub>	Input Data Pad-to-Y LOW	1.5		1.7		1.9		2.2		ns
Predicted Input Routing Delays <sup>2</sup>										
t <sub>IRD1</sub>	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t <sub>IRD2</sub>	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t <sub>IRD3</sub>	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t <sub>IRD4</sub>	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t <sub>IRD8</sub>	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t <sub>IRD12</sub>	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns

### Notes:

- For dual-module macros, use  $t_{PD} + t_{RD1} + t_{PDn}$ ,  $t_{RCO} + t_{RD1} + t_{PDn}$ , or  $t_{PD1} + t_{RD1} + t_{SUD}$ , whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except  $t_{ENZL}$  and  $t_{ENZH}$ . For  $t_{ENZL}$  and  $t_{ENZH}$ , the loading is 5 pF.

**Table 1-18 • A54SX16 Timing Characteristics (Continued)**  
**(Worst-Case Commercial Conditions,  $V_{CCR} = 4.75\text{ V}$ ,  $V_{CCA}, V_{CCI} = 3.0\text{ V}$ ,  $T_J = 70^\circ\text{C}$ )**

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t <sub>HCKH</sub>	Input LOW to HIGH (pad to R-Cell input)	1.2		1.4		1.5		1.8		ns
t <sub>HCKL</sub>	Input HIGH to LOW (pad to R-Cell input)	1.2		1.4		1.6		1.9		ns
t <sub>HPWH</sub>	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t <sub>HPWL</sub>	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t <sub>HCKSW</sub>	Maximum Skew	0.2		0.2		0.3		0.3		ns
t <sub>HP</sub>	Minimum Period	2.7		3.1		3.6		4.2		ns
f <sub>HMAX</sub>	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t <sub>RCKH</sub>	Input LOW to HIGH (light load) (pad to R-Cell input)	1.6		1.8		2.1		2.5		ns
t <sub>RCKL</sub>	Input HIGH to LOW (light load) (pad to R-Cell input)	1.8		2.0		2.3		2.7		ns
t <sub>RCKH</sub>	Input LOW to HIGH (50% load) (pad to R-Cell input)	1.8		2.1		2.5		2.8		ns
t <sub>RCKL</sub>	Input HIGH to LOW (50% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t <sub>RCKH</sub>	Input LOW to HIGH (100% load) (pad to R-Cell input)	1.8		2.1		2.4		2.8		ns
t <sub>RCKL</sub>	Input HIGH to LOW (100% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t <sub>RPWH</sub>	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t <sub>RPWL</sub>	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t <sub>RCKSW</sub>	Maximum Skew (light load)	0.5		0.5		0.5		0.7		ns
t <sub>RCKSW</sub>	Maximum Skew (50% load)	0.5		0.6		0.7		0.8		ns
t <sub>RCKSW</sub>	Maximum Skew (100% load)	0.5		0.6		0.7		0.8		ns
TTL Output Module Timing <sup>3</sup>										
t <sub>DLH</sub>	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t <sub>DHL</sub>	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t <sub>ENZL</sub>	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t <sub>ENZH</sub>	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t <sub>ENLZ</sub>	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns
t <sub>ENHZ</sub>	Enable-to-Pad, H to Z	1.3		1.5		1.7		2.0		ns

**Notes:**

- For dual-module macros, use  $t_{PD} + t_{RD1} + t_{PDn}$ ,  $t_{RCO} + t_{RD1} + t_{PDn}$ , or  $t_{PD1} + t_{RD1} + t_{SUD}$ , whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except  $t_{ENZL}$  and  $t_{ENZH}$ . For  $t_{ENZL}$  and  $t_{ENZH}$ , the loading is 5 pF.

Table 1-19 • A54SX16P Timing Characteristics (Continued)

(Worst-Case Commercial Conditions,  $V_{CCR} = 4.75\text{ V}$ ,  $V_{CCA}, V_{CCI} = 3.0\text{ V}$ ,  $T_J = 70^\circ\text{C}$ )

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t <sub>HCKH</sub>	Input LOW to HIGH (pad to R-Cell input)	1.2		1.4		1.5		1.8		ns
t <sub>HCKL</sub>	Input HIGH to LOW (pad to R-Cell input)	1.2		1.4		1.6		1.9		ns
t <sub>HPWH</sub>	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t <sub>HPWL</sub>	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t <sub>HCKSW</sub>	Maximum Skew	0.2		0.2		0.3		0.3		ns
t <sub>HP</sub>	Minimum Period	2.7		3.1		3.6		4.2		ns
f <sub>HMAX</sub>	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t <sub>RCKH</sub>	Input LOW to HIGH (light load) (pad to R-Cell input)	1.6		1.8		2.1		2.5		ns
t <sub>RCKL</sub>	Input HIGH to LOW (Light Load) (pad to R-Cell input)	1.8		2.0		2.3		2.7		ns
t <sub>RCKH</sub>	Input LOW to HIGH (50% load) (pad to R-Cell input)	1.8		2.1		2.5		2.8		ns
t <sub>RCKL</sub>	Input HIGH to LOW (50% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t <sub>RCKH</sub>	Input LOW to HIGH (100% load) (pad to R-Cell input)	1.8		2.1		2.4		2.8		ns
t <sub>RCKL</sub>	Input HIGH to LOW (100% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t <sub>RPWH</sub>	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t <sub>RPWL</sub>	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t <sub>RCKSW</sub>	Maximum Skew (light load)	0.5		0.5		0.5		0.7		ns
t <sub>RCKSW</sub>	Maximum Skew (50% load)	0.5		0.6		0.7		0.8		ns
t <sub>RCKSW</sub>	Maximum Skew (100% load)	0.5		0.6		0.7		0.8		ns
TTL Output Module Timing										
t <sub>DLH</sub>	Data-to-Pad LOW to HIGH	2.4		2.8		3.1		3.7		ns
t <sub>DHL</sub>	Data-to-Pad HIGH to LOW	2.3		2.9		3.2		3.8		ns
t <sub>ENZL</sub>	Enable-to-Pad, Z to L	3.0		3.4		3.9		4.6		ns
t <sub>ENZH</sub>	Enable-to-Pad, Z to H	3.3		3.8		4.3		5.0		ns
t <sub>ENLZ</sub>	Enable-to-Pad, L to Z	2.3		2.7		3.0		3.5		ns
t <sub>ENHZ</sub>	Enable-to-Pad, H to Z	2.8		3.2		3.7		4.3		ns

**Note:**

- For dual-module macros, use  $t_{PD} + t_{RD1} + t_{PDn}$ ,  $t_{RCO} + t_{RD1} + t_{PDn}$ , or  $t_{PD1} + t_{RD1} + t_{SUD}$ , whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 10 pF loading.



# Package Pin Assignments

## 84-Pin PLCC

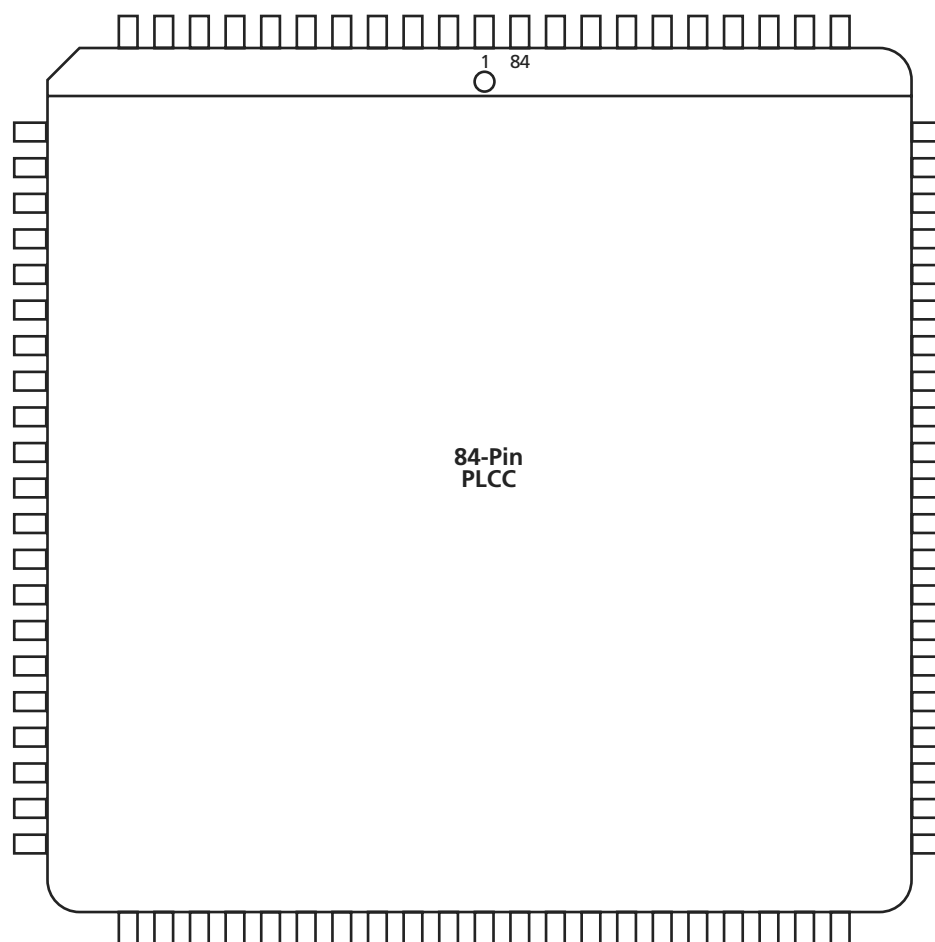


Figure 2-1 • 84-Pin PLCC (Top View)

### Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

84-Pin PLCC	
Pin Number	A54SX08 Function
1	V <sub>CCR</sub>
2	GND
3	V <sub>CCA</sub>
4	PRA, I/O
5	I/O
6	I/O
7	V <sub>CCI</sub>
8	I/O
9	I/O
10	I/O
11	TCK, I/O
12	TDI, I/O
13	I/O
14	I/O
15	I/O
16	TMS
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O
22	I/O
23	I/O
24	I/O
25	I/O
26	I/O
27	GND
28	V <sub>CCI</sub>
29	I/O
30	I/O
31	I/O
32	I/O
33	I/O
34	I/O
35	I/O

84-Pin PLCC	
Pin Number	A54SX08 Function
36	I/O
37	I/O
38	I/O
39	I/O
40	PRB, I/O
41	V <sub>CCA</sub>
42	GND
43	V <sub>CCR</sub>
44	I/O
45	HCLK
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	TDO, I/O
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	I/O
59	V <sub>CCA</sub>
60	V <sub>CCI</sub>
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	V <sub>CCA</sub>
69	GND
70	I/O

84-Pin PLCC	
Pin Number	A54SX08 Function
71	I/O
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	CLKA
84	CLKB

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
73	NC	I/O	I/O
74	I/O	I/O	I/O
75	NC	I/O	I/O
76	PRB, I/O	PRB, I/O	PRB, I/O
77	GND	GND	GND
78	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
79	GND	GND	GND
80	V <sub>CCR</sub>	V <sub>CCR</sub>	V <sub>CCR</sub>
81	I/O	I/O	I/O
82	HCLK	HCLK	HCLK
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	NC	I/O	I/O
86	I/O	I/O	I/O
87	I/O	I/O	I/O
88	NC	I/O	I/O
89	I/O	I/O	I/O
90	I/O	I/O	I/O
91	NC	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	NC	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	NC	I/O	I/O
98	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
99	I/O	I/O	I/O
100	I/O	I/O	I/O
101	I/O	I/O	I/O
102	I/O	I/O	I/O
103	TDO, I/O	TDO, I/O	TDO, I/O
104	I/O	I/O	I/O
105	GND	GND	GND
106	NC	I/O	I/O
107	I/O	I/O	I/O
108	NC	I/O	I/O

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
109	I/O	I/O	I/O
110	I/O	I/O	I/O
111	I/O	I/O	I/O
112	I/O	I/O	I/O
113	I/O	I/O	I/O
114	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
115	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
116	NC	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	NC	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	NC	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	NC	I/O	I/O
126	I/O	I/O	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	GND	GND	GND
130	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
131	GND	GND	GND
132	V <sub>CCR</sub>	V <sub>CCR</sub>	V <sub>CCR</sub>
133	I/O	I/O	I/O
134	I/O	I/O	I/O
135	NC	I/O	I/O
136	I/O	I/O	I/O
137	I/O	I/O	I/O
138	NC	I/O	I/O
139	I/O	I/O	I/O
140	I/O	I/O	I/O
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	NC	I/O	I/O
144	I/O	I/O	I/O

**Note:** \* Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).



208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
145	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
146	GND	GND	GND
147	I/O	I/O	I/O
148	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	NC	I/O	I/O
156	NC	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	NC	I/O	I/O
168	I/O	I/O	I/O
169	I/O	I/O	I/O
170	NC	I/O	I/O
171	I/O	I/O	I/O
172	I/O	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	NC	I/O	I/O
177	I/O	I/O	I/O
178	I/O	I/O	I/O
179	I/O	I/O	I/O
180	CLKA	CLKA	CLKA

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
181	CLKB	CLKB	CLKB
182	V <sub>CCR</sub>	V <sub>CCR</sub>	V <sub>CCR</sub>
183	GND	GND	GND
184	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
185	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O
188	I/O	I/O	I/O
189	NC	I/O	I/O
190	I/O	I/O	I/O
191	I/O	I/O	I/O
192	NC	I/O	I/O
193	I/O	I/O	I/O
194	I/O	I/O	I/O
195	NC	I/O	I/O
196	I/O	I/O	I/O
197	I/O	I/O	I/O
198	NC	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
202	NC	I/O	I/O
203	NC	I/O	I/O
204	I/O	I/O	I/O
205	NC	I/O	I/O
206	I/O	I/O	I/O
207	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O

**Note:** \* Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
69	HCLK	HCLK	HCLK
70	I/O	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	I/O	I/O	I/O
79	NC	I/O	I/O
80	I/O	I/O	I/O
81	NC	I/O	I/O
82	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	I/O	I/O
86	I/O	I/O	I/O
87	TDO, I/O	TDO, I/O	TDO, I/O
88	I/O	I/O	I/O
89	GND	GND	GND
90	NC	I/O	I/O
91	NC	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	I/O	I/O	I/O
98	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
99	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
100	I/O	I/O	I/O
101	I/O	I/O	I/O
102	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
103	I/O	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	I/O	I/O	I/O
107	I/O	I/O	I/O
108	GND	GND	GND
109	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
110	GND	GND	GND
111	I/O	I/O	I/O
112	I/O	I/O	I/O
113	I/O	I/O	I/O
114	I/O	I/O	I/O
115	I/O	I/O	I/O
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	NC	I/O	I/O
119	I/O	I/O	I/O
120	NC	I/O	I/O
121	NC	I/O	I/O
122	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>
123	GND	GND	GND
124	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
125	I/O	I/O	I/O
126	I/O	I/O	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	I/O	I/O	I/O
130	I/O	I/O	I/O
131	NC	I/O	I/O
132	NC	I/O	I/O
133	GND	GND	GND
134	I/O	I/O	I/O
135	I/O	I/O	I/O
136	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
141	I/O	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	I/O	I/O	I/O
146	I/O	I/O	I/O
147	I/O	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	CLKA	CLKA	CLKA
153	CLKB	CLKB	CLKB
154	V <sub>CCR</sub>	V <sub>CCR</sub>	V <sub>CCR</sub>
155	GND	GND	GND
156	V <sub>CCA</sub>	V <sub>CCA</sub>	V <sub>CCA</sub>

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
157	PRA, I/O	PRA, I/O	PRA, I/O
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	V <sub>CCI</sub>	V <sub>CCI</sub>	V <sub>CCI</sub>
170	I/O	I/O	I/O
171	NC	I/O	I/O
172	NC	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	TCK, I/O	TCK, I/O	TCK, I/O

313-Pin PBGA		313-Pin PBGA		313-Pin PBGA		313-Pin PBGA	
Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function
H20	I/O	L25	I/O	R5	I/O	V10	I/O
H22	V <sub>CCI</sub>	M2	I/O	R7	I/O	V12	I/O
H24	I/O	M4	I/O	R9	I/O	V14	I/O
J1	I/O	M6	I/O	R11	I/O	V16	NC
J3	I/O	M8	I/O	R13	GND	V18	I/O
J5	I/O	M10	I/O	R15	I/O	V20	I/O
J7	NC	M12	GND	R17	I/O	V22	V <sub>CCA</sub>
J9	I/O	M14	GND	R19	I/O	V24	V <sub>CCI</sub>
J11	I/O	M16	V <sub>CCI</sub>	R21	I/O	W1	I/O
J13	CLKA	M18	I/O	R23	I/O	W3	I/O
J15	I/O	M20	I/O	R25	I/O	W5	I/O
J17	I/O	M22	I/O	T2	I/O	W7	NC
J19	I/O	M24	I/O	T4	I/O	W9	I/O
J21	GND	N1	I/O	T6	I/O	W11	I/O
J23	I/O	N3	V <sub>CCA</sub>	T8	I/O	W13	V <sub>CCI</sub>
J25	I/O	N5	V <sub>CCR</sub>	T10	I/O	W15	I/O
K2	I/O	N7	I/O	T12	I/O	W17	I/O
K4	I/O	N9	V <sub>CCI</sub>	T14	HCLK	W19	I/O
K6	I/O	N11	GND	T16	I/O	W21	I/O
K8	V <sub>CCI</sub>	N13	GND	T18	I/O	W23	I/O
K10	I/O	N15	GND	T20	I/O	W25	I/O
K12	I/O	N17	I/O	T22	I/O	Y2	I/O
K14	I/O	N19	I/O	T24	I/O	Y4	I/O
K16	I/O	N21	I/O	U1	I/O	Y6	I/O
K18	I/O	N23	V <sub>CCR</sub>	U3	I/O	Y8	I/O
K20	V <sub>CCA</sub>	N25	V <sub>CCA</sub>	U5	V <sub>CCI</sub>	Y10	I/O
K22	I/O	P2	I/O	U7	I/O	Y12	I/O
K24	I/O	P4	I/O	U9	I/O	Y14	I/O
L1	I/O	P6	I/O	U11	I/O	Y16	I/O
L3	I/O	P8	I/O	U13	I/O	Y18	I/O
L5	I/O	P10	I/O	U15	I/O	Y20	NC
L7	I/O	P12	GND	U17	I/O	Y22	I/O
L9	I/O	P14	GND	U19	I/O	Y24	NC
L11	I/O	P16	I/O	U21	I/O		
L13	GND	P18	I/O	U23	I/O		
L15	I/O	P20	NC	U25	I/O		
L17	I/O	P22	I/O	V2	V <sub>CCA</sub>		
L19	I/O	P24	I/O	V4	I/O		
L21	I/O	R1	I/O	V6	I/O		
L23	I/O	R3	I/O	V8	I/O		

# Datasheet Information

## List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous Version	Changes in Current Version (v3.2)	Page
v3.1 (June 2003)	The "Ordering Information" was updated to include RoHS information.	1-ii
	The Product Plan was removed since all products have been released.	N/A
	Information concerning the TRST pin in the "Probe Circuit Control Pins" section was removed.	1-6
	The "Dedicated Test Mode" section is new.	1-6
	The "Programming" section is new.	1-7
	A note was added to the "Power-Up Sequencing" table.	1-15
	A note was added to the "Power-Down Sequencing" table. The 3.3 V comments were updated for the following devices: A54SX08, A54SX16, A54SX32.	1-15
	U11 and U13 were added to the "313-Pin PBGA" table.	2-17
v3.0.1	Storage temperature in Table 1-3 was updated.	1-7
	Table 1-1 was updated.	1-5

## Datasheet Categories

In order to provide the latest information to designers, some datasheets are published before data has been fully characterized. Datasheets are designated as "Product Brief," "Advanced," "Production," and "Datasheet Supplement." The definitions of these categories are as follows:

### Product Brief

The product brief is a summarized version of a datasheet (advanced or production) containing general product information. This brief gives an overview of specific device and family information.

### Advanced

This datasheet version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production.

### Unmarked (production)

This datasheet version contains information that is considered to be final.

### Datasheet Supplement

The datasheet supplement gives specific device information for a derivative family that differs from the general family datasheet. The supplement is to be used in conjunction with the datasheet to obtain more detailed information and for specifications that do not differ between the two families.

## International Traffic in Arms Regulations (ITAR) and Export Administration Regulations (EAR)

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